

<i>N t i c o f R e f e r e n c e s C i t e d</i>	Application/Control No. 09/931,104	Applicant(s)/Patent Under Reexamination YOSHIDA, EIJI	
	Examiner Johannes P Mondt	Art Unit 2826	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,084,267	07-2000	Petrosino	257/341
	B	US-			
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	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.